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T-Mapping diagnostic system for vertical test of SHINE superconducting cavity

Wednesday, 22 May 2024 16:00 (2 hours)

T-mapping diagnostic system is an indirect method to detect the internal surface of superconducting cavity during vertical testing. When superconducting cavity is powered, T-Mapping can detect the thermal instability and thermal collapse caused by defects. The goal of the project is to develop temperature detection devices that are highly accurate and easy to install. The development of the equipment plays a supporting role in the production of superconducting cavity, and can intuitive feedback the defects in the machining assembly, which is conducive to the improvement of the processing technology.

Footnotes

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